

200V P-Channel Enhancement-Mode MOSFET

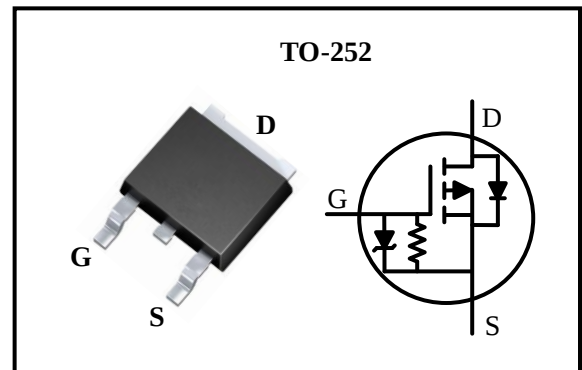
General Features

- Rugged Polysilicon Gate Cell Structure
- Integrated Gate-to-Source Resistor
- Integrated Gate-to-Source Zener Diode
- Low On-Resistance
- Low Threshold
- Low Input Capacitance
- Low Input and Output Leakage
- Fast Switching Speeds
- Free from Secondary Breakdown
- Halogen-free Available
- RoHS Compliant

BV_{DSX}	$R_{DS(ON)} (Max.)$	I_D
-200V	6Ω	-2A

Applications

- Amplifiers
- Buffers
- General Purpose Line Drivers
- High-Voltage Pulsers
- Logic-level Interfaces
- Piezoelectric Transducer Drivers



Ordering Information

Part Number	Package	Marking	Remark
FTD03P20G	TO-252	03P20	Halogen Free

Absolute Maximum Ratings

$T_A = 25^\circ\text{C}$ unless otherwise specified

Symbol	Parameter	FTD03P20G	Unit
V_{DSX}	Drain-to-Source Voltage ^[1]	-200	V
V_{DGX}	Drain-to-Gate Voltage ^[1]	-200	V
I_D	Continuous Drain Current	-2	A
I_{DM}	Pulsed Drain Current ^[2]	-6	
P_D	Power Dissipation	36	W
T_L	Soldering Temperature Distance of 1.6mm from case for 10 seconds	300	$^\circ\text{C}$
T_J & T_{STG}	Operating and Storage Temperature Range	-55 to 150	

Caution: Stresses greater than those listed in the "Absolute Maximum Ratings" may cause permanent damage to the device.

Thermal Characteristics

Symbol	Parameter	FTD03P20G	Unit
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	3.47	$^\circ\text{C}/\text{W}$

Electrical Characteristics

OFF Characteristics

 $T_A = 25^\circ\text{C}$ unless otherwise specified

Symbol	Parameter	Min.	Typ.	Max.	Unit	Test Conditions
BV_{DSX}	Drain-to-Source Breakdown Voltage	-200	--	--	V	$V_{GS}=0V$, $I_D=-250\mu A$
I_{DSS}	Drain-to-Source Leakage Current	--	--	-10	μA	$V_{DS}=-200V$, $V_{GS}=0V$
R_{GS}	Gate-to-source Shunt Resistor	10	--	50	$k\Omega$	$I_{GS} = 100\mu A$
V_{ZGS}	Gate-to-Source Zener Voltage	13	--	25	V	$I_{GS} = -2mA$

ON Characteristics

 $T_A = 25^\circ\text{C}$ unless otherwise specified

Symbol	Parameter	Min.	Typ.	Max.	Unit	Test Conditions
$I_{D(ON)}$	On- Drain-to-Source Drain Current	-1	--	--	A	$V_{GS} = -4.5V$, $V_{DS} = -25V$
		-2	--	--	A	$V_{GS} = -10V$, $V_{DS} = -25V$
$R_{DS(ON)}$	Static Drain-to-Source On-Resistance	--	--	6	Ω	$V_{GS}=-4.5V$, $I_D=-150mA$ ^[3]
		--	--	5	Ω	$V_{GS}=-10V$, $I_D=-1A$ ^[3]
$V_{GS(TH)}$	Gate Threshold Voltage	-1	--	-2.4	V	$V_{GD}=0V$, $I_D=-250\mu A$
gfs	Forward Transconductance	0.4	--	--	S	$V_{DS}=-25V$, $I_D=-500mA$

Dynamic Characteristics

Essentially independent of operating temperature

Symbol	Parameter	Min.	Typ.	Max.	Unit	Test Conditions
C_{iss}	Input Capacitance	--	228.3	--	pF	$V_{GS}=0V$ $V_{DS}=-25V$ $f=1.0MHz$
C_{oss}	Output Capacitance	--	35.5	--		
C_{rss}	Reverse Transfer Capacitance	--	6.4	--		
Q_g	Total Gate Charge	--	6.5	--	nC	$V_{GS}=-10V$ $V_{DS}=-25V$ $I_D=-1A$
Q_{gs}	Gate-to-Source Charge	--	0.87	--		
Q_{gd}	Gate-to-Drain (Miller) Charge	--	0.6	--		

Resistive Switching Characteristics

Essentially independent of operating temperature

Symbol	Parameter	Min.	Typ.	Max.	Unit	Test Conditions
$t_{d(on)}$	Turn-on Delay Time	--	3.8	--	ns	$V_{GS}=-10V$ $V_{DD}=-25V$ $I_D=-1A$ $R_G=25\Omega$
t_{rise}	Rise Time	--	8.9	--		
$t_{d(off)}$	Turn-off Delay Time	--	18.8	--		
t_{fall}	Fall Time	--	6.6	--		



Source-Drain Diode Characteristics

$T_A=25^{\circ}\text{C}$ unless otherwise specified

Symbol	Parameter	Min	Typ.	Max.	Unit	Test Conditions
V_{SD}	Diode Forward Voltage	--	--	-2.0	V	$I_{SD}=-500\text{mA}$, $V_{GS}=0\text{V}$

NOTE:

[1] $T_J=+25^{\circ}\text{C}$ to $+150^{\circ}\text{C}$.

[2] Repetitive rating, pulse width limited by maximum junction temperature.

[3] Pulse width $\leq 380\mu\text{s}$, duty cycle $\leq 2\%$.

Typical Characteristics

Figure 1. Maximum Power Dissipation vs. Case Temperature

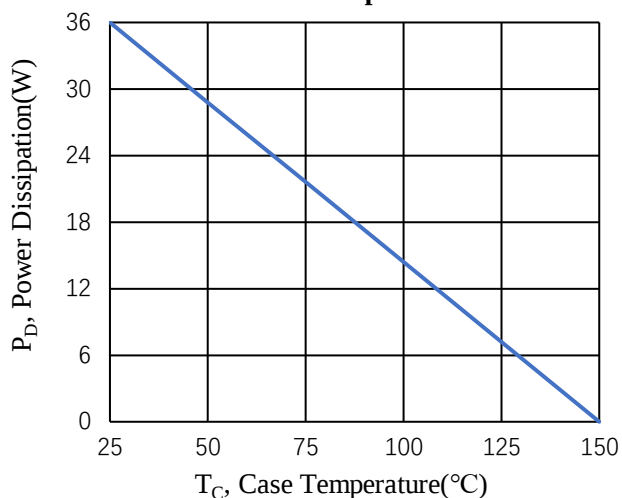


Figure 2. Maximum Continuous Drain Current vs. Case Temperature

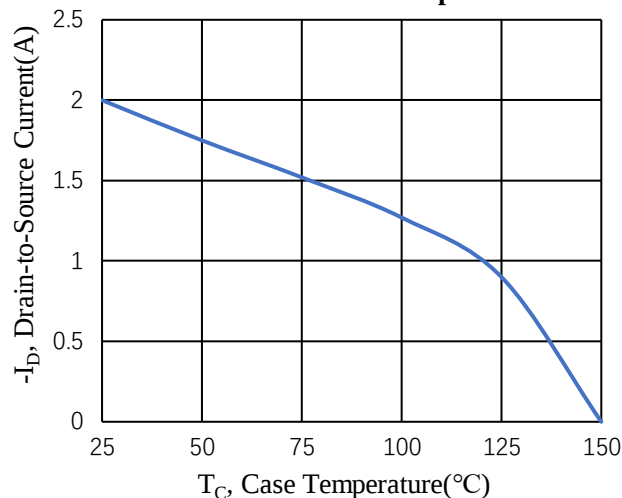


Figure 3. Typical Output Characteristics

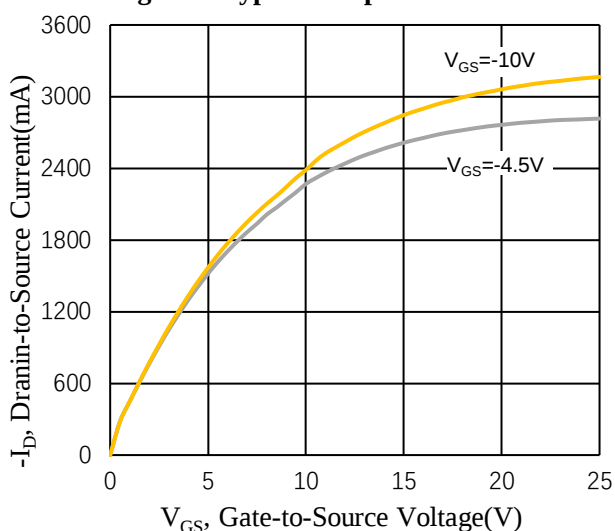


Figure 4. Typical Transfer Characteristics

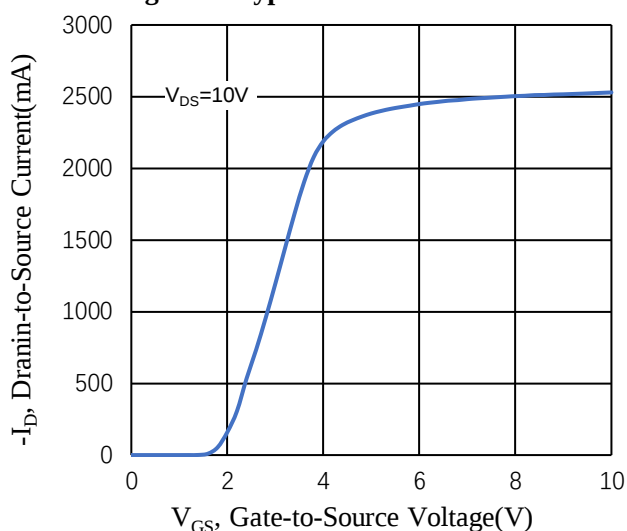


Figure 5. Typical Capacitance vs. Drain-to-Source Voltage

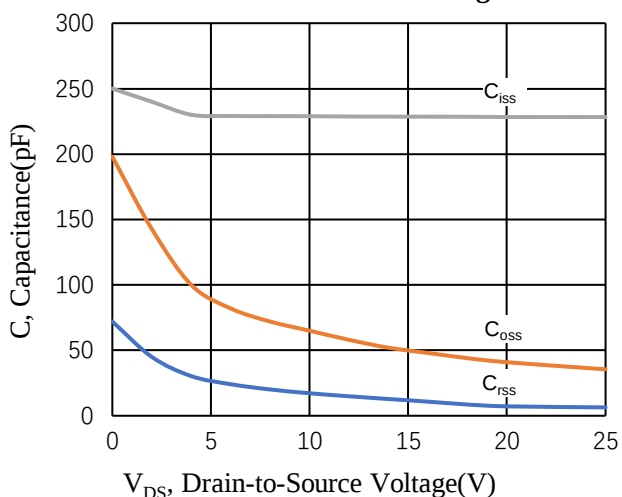


Figure 6. Typical Gate Charge vs. Gate-to-Source Voltage

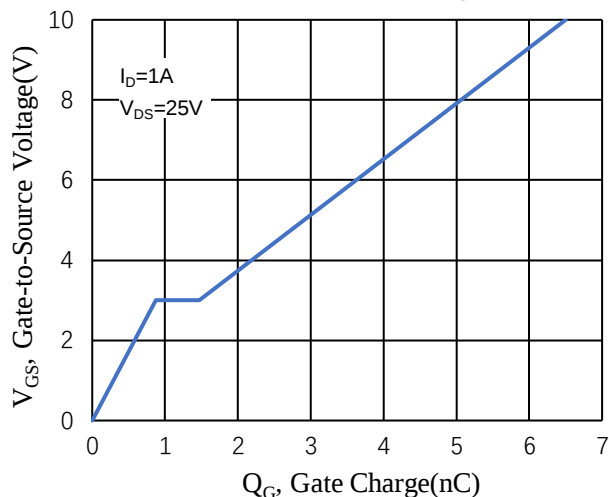


Figure 7. Threshold Voltage vs. Temperature

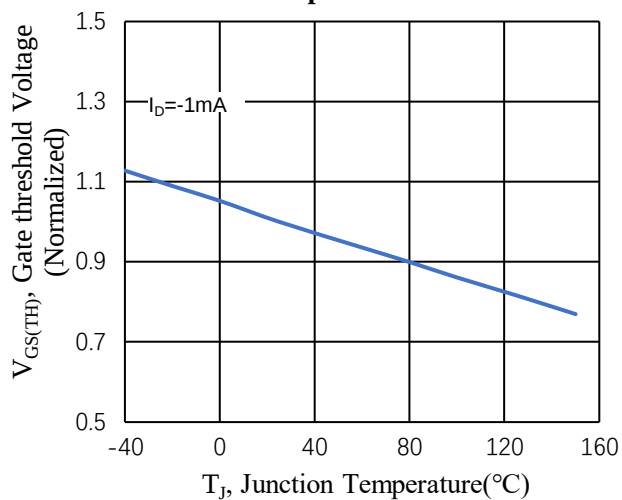


Figure 8. On-Resistance vs. Junction Temperature

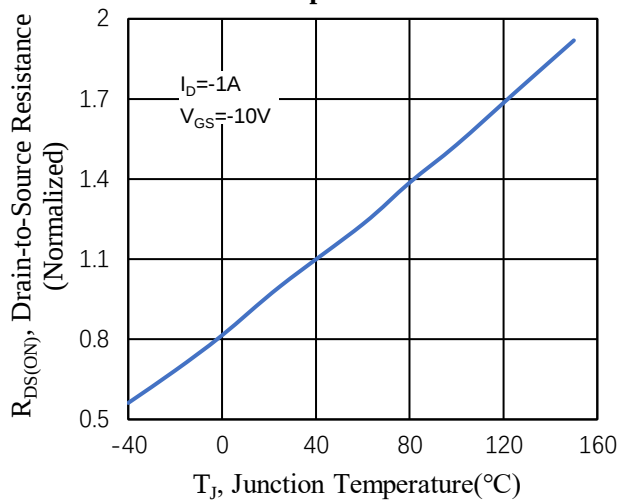


Figure 9. Drain-to-Source Breakdown Voltage vs. Junction Temperature

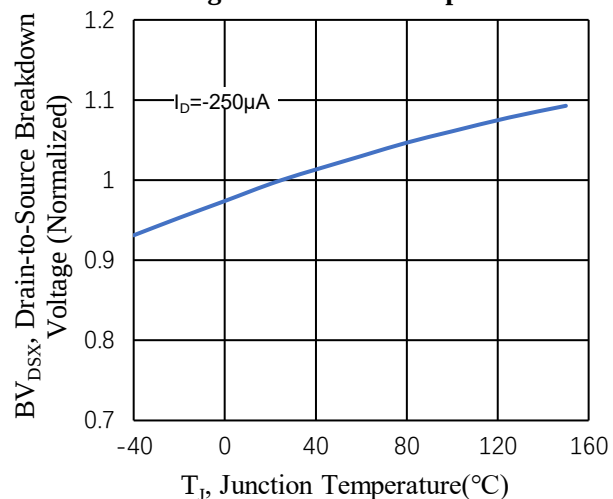
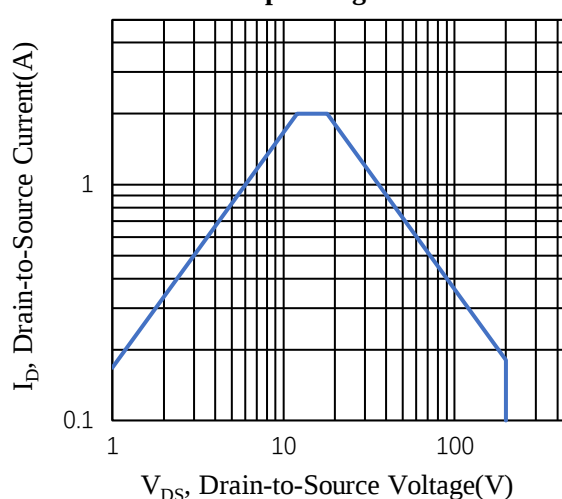
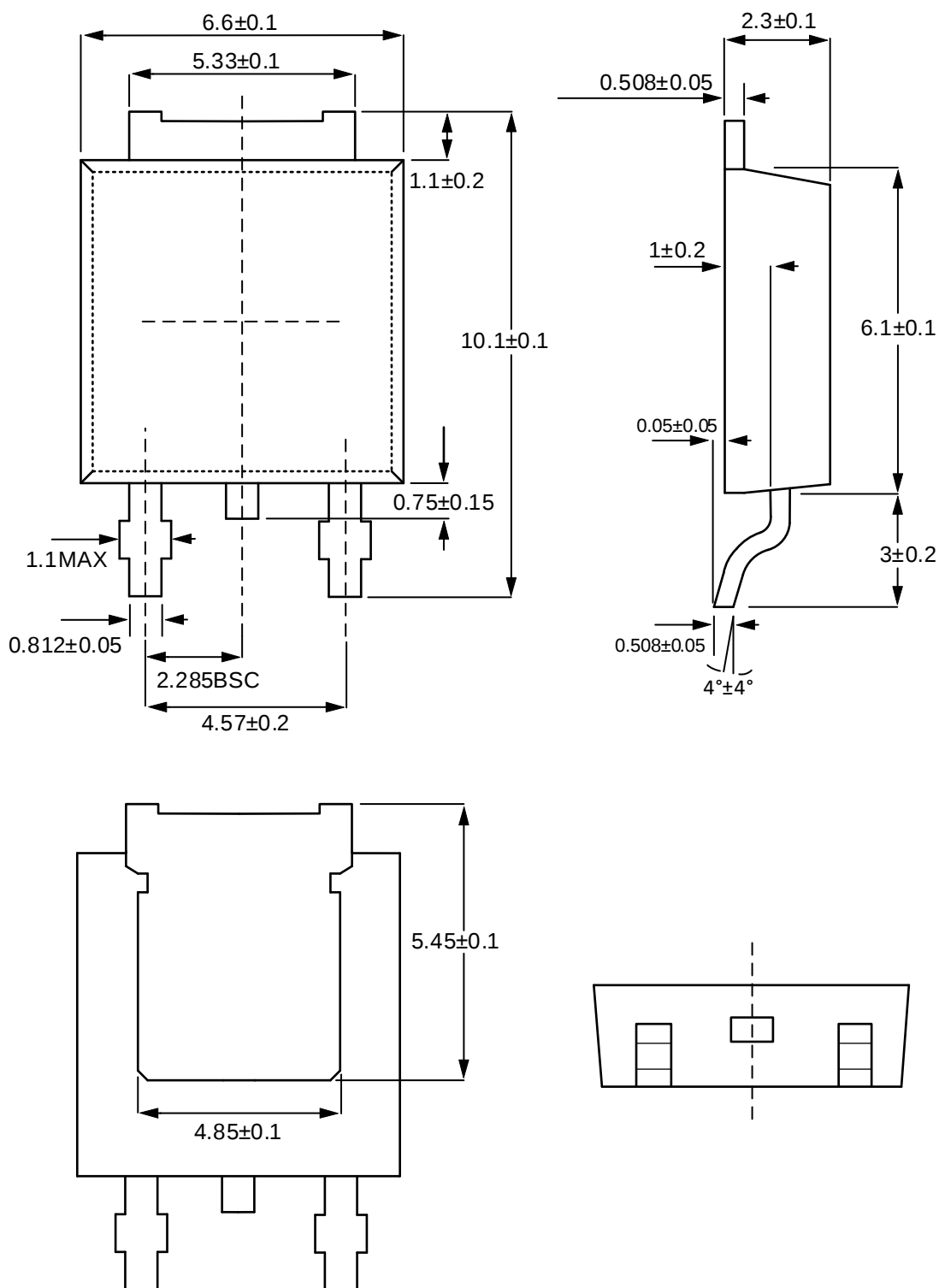


Figure 10. Maximum Forward Safe Operating Area



Package Dimensions

TO-252





Published by

ARK Microelectronics Co., Ltd.

ADD: 4F, D26, UESTC National Science Park No. 1 Shuangxing Avenue, Chengdu, Sichuan.

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